organic papers

Ethyl 4-butylamino-2-chloroquinoline-3-carboxylate

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Key indicators

Single-crystal X-ray study
T = 290 K
Mean σ(C–C) = 0.002 Å
R factor = 0.038
wR factor = 0.072
Data-to-parameter ratio = 20.3

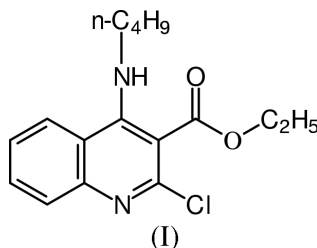For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.

The title molecule, $C_{16}H_{19}ClN_2O_2$, contains three planar fragments, *i.e.* the quinoline system (A), the butylamino group (B) and the carboxyl group (C). Angles A/B and A/C are 9.1 (2) and 79.08 (4)°, respectively. The alternation of the bond lengths in the quinoline bicycle correlates with literature data.

Comment

During investigation of the reaction of ethyl 2,4-dichloro-quinoline-3-carboxylate with nucleophilic reagents, it was found that this compound reacts with sodium acetate giving ethyl chloro-2-oxo-1,2-dihydroquinoline-3-carboxylate, as identified in previous work (Ukrainets *et al.*, 1995). However, X-ray diffraction analysis has shown the product of this reaction to be ethyl 4-butylamino-2-chloroquinoline-3-carboxylate, (I), the structure of which is presented here.

(I)

The quinoline fragment of (I) (Fig. 1) is planar within 0.02 Å. The Cl atom lies in the plane of the quinoline bicycle. The carboxyl group is rotated by 79.08 (4)° with respect to the quinoline fragment [the C2—C3—C11—O1 and C2—C3—C11—O2 torsion angles are 95.7 (1) and −81.7 (1)°, respectively]. The non-H atoms of the butylamine fragment are coplanar within 0.03 Å and this plane is rotated by 9.1 (2)° with respect to the quinoline fragment. This rotation may be caused by steric repulsion between the H5 and H2 atoms, [the distance is 2.05 (2) Å and the sum of the van der Waals radii is 2.32 Å].

A noticeable alternation of the C—C (C—N) bonds is observed within the quinoline fragment, *i.e.* the N1—C2, C3—C4, C5—C6 and C7—C8 bonds are shorter and the remaining bonds are longer than the mean value for aromatic C—C bonds (1.387 Å; Bürgi & Dunitz, 1994). Such a feature is observed also for other quinoline-containing structures (Merlino, 1968; Blackburn *et al.*, 1996; Chiang *et al.*, 1991; Gdaniec *et al.*, 1980; Gdaniec & Dziembowska, 1980; Ahmet *et al.*, 1995).
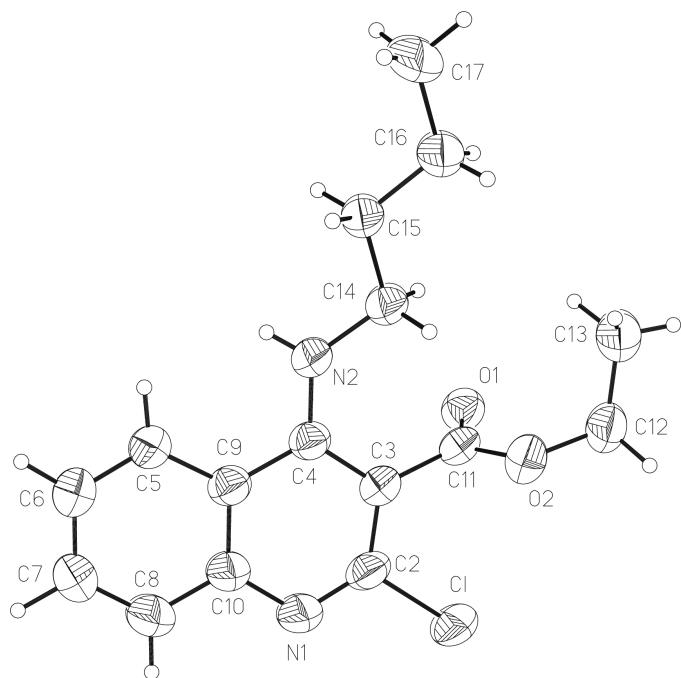
Table 1
Selected geometric parameters (Å, °).

Cl—C2	1.7818 (11)	C4—C9	1.4579 (15)
O1—C11	1.2245 (13)	C5—C6	1.3719 (18)
O2—C11	1.3425 (13)	C5—C9	1.4376 (15)
O2—C12	1.4712 (15)	C6—C7	1.4203 (19)
N1—C2	1.3057 (14)	C7—C8	1.3662 (18)
N1—C10	1.3914 (14)	C8—C10	1.4250 (17)
N2—C4	1.3715 (13)	C9—C10	1.4318 (15)
N2—C14	1.4638 (15)	C12—C13	1.517 (2)
C2—C3	1.4222 (14)	C14—C15	1.5321 (15)
C3—C4	1.4202 (14)	C15—C16	1.5322 (17)
C3—C11	1.5080 (15)	C16—C17	1.527 (2)
C11—O2—C12	117.34 (10)	C7—C8—C10	121.11 (12)
C2—N1—C10	116.14 (9)	C10—C9—C5	117.51 (10)
C4—N2—C14	127.57 (9)	C10—C9—C4	118.84 (9)
N1—C2—C3	128.43 (10)	C5—C9—C4	123.65 (10)
N1—C2—Cl	114.37 (8)	N1—C10—C8	117.95 (10)
C3—C2—Cl	117.13 (9)	N1—C10—C9	122.30 (10)
C4—C3—C2	116.56 (10)	C8—C10—C9	119.75 (10)
C4—C3—C11	124.01 (9)	O1—C11—O2	123.84 (10)
C2—C3—C11	118.59 (9)	O1—C11—C3	122.10 (10)
N2—C4—C3	123.84 (10)	O2—C11—C3	114.01 (9)
N2—C4—C9	118.58 (9)	O2—C12—C13	111.68 (11)
C3—C4—C9	117.57 (9)	N2—C14—C15	110.43 (9)
C6—C5—C9	120.92 (11)	C16—C15—C14	112.80 (9)
C5—C6—C7	120.99 (12)	C17—C16—C15	112.46 (12)
C8—C7—C6	119.68 (13)		

Figure 1
Numbering scheme and displacement ellipsoids for the title compound (50% probability level).

Experimental

Crystals of (I) suitable for X-ray study were grown *via* the slow evaporation of an alcohol solution.

Crystal data

C$_{16}$H$_{19}$ClN$_2$O$_2$
M_r = 306.78
Triclinic, $P\bar{1}$
a = 8.174 (2) Å
b = 8.760 (2) Å
c = 11.793 (2) Å
α = 75.68 (2)°
β = 85.77 (2)°
γ = 84.98 (2)°
V = 813.9 (3) Å^3

Z = 2
D_x = 1.252 Mg m^{-3}
Mo $K\alpha$ radiation
Cell parameters from 34 reflections
θ = 13.0–15.0°
μ = 0.24 mm^{-1}
T = 290 (2) K
Elongated prism, colourless
0.45 × 0.40 × 0.25 mm

Data collection

Siemens *P*3/*PC* diffractometer
2θ/θ scans
Absorption correction: by integration (*XPREP*; Siemens, 1991)
T_{min} = 0.887, T_{max} = 0.945
5630 measured reflections
5401 independent reflections
2629 reflections with $I > 2\sigma(I)$

R_{int} = 0.054
θ_{max} = 32.5°
h = −12 → 12
k = −12 → 13
l = 0 → 16
2 standard reflections
    every 98 reflections
    intensity decay: 2%

Refinement

Refinement on F^2
$R[F^2 > 2\sigma(F^2)]$ = 0.038
$wR(F^2)$ = 0.072
S = 0.91
5401 reflections
266 parameters

All H-atom parameters refined
$w = 1/[\sigma^2(F_o^2) + (0.0213P)^2]$
    where P F_o^2 + 2F_c^2)/3
$(\Delta/\sigma)_{max}$ = 0.004
$\Delta\rho_{max}$ = 0.16 e Å^{-3}
$\Delta\rho_{min}$ = −0.12 e Å^{-3}

Data collection: *P*3 (Siemens, 1989); cell refinement: P3; data reduction: *XDISK* (Siemens, 1991); program(s) used to solve structure: *SHELXS*97 (Sheldrick, 1990); program(s) used to refine structure: *SHELXL*97 (Sheldrick, 1997); molecular graphics: *XP* (Siemens, 1991); software used to prepare material for publication: *SHELXL*97.

References

Ahmet, M. T., Miller, J. R., Osborne, A. G. & Warmsley, J. F. (1995). *Acta Cryst.* C**51**, 2105–2108.
Blackburn, A. C., Dobson, A. J. & Gerkin, R. E. (1996). *Acta Cryst.* C**52**, 409–411.
Bürgi, H.-B. & Dunitz, J. D. (1994). Editors. *Structure Correlation*, Vol. 2, p. 771. Weinheim, New York, Basel, Cambridge, Tokyo: Verlag VCH.
Chiang, L. Y, Swirczewski, J. W., Kastrup, R., Hsu, C. S. & Upasani, R. B. (1991). *J. Am. Chem. Soc.* **113**, 6574–6579.
Gdaniec, M. & Dziembowska, T. (1980). *Pol. J. Chem.* **54**, 87–94.
Gdaniec, M., Jaskolski, M. & Kosturkiewicz, Z. (1980). *Pol. J. Chem.* **54**, 1539–1544.
Merlino, S. (1968). *Atti Accad. Naz. Lincei*, **45**, 60–65.
Sheldrick, G. M. (1990). *Acta Cryst.* A**46**, 467–473.
Sheldrick, G. M. (1997). *SHELXL*97. University of Göttingen, Germany.
Siemens (1989). *P*3. Siemens Analytical X-ray Instruments Inc., Karlsruhe, Germany.
Siemens (1991). *XDISK*, *XPREP* and *XP*. Siemens Analytical X-ray Instruments Inc., Karlsruhe, Germany.
Ukrainets, I. V., Taran, S. G., Gorokhova, O. V., Marusenko, N. A., Kovalenko, S. N., Turov, A. V., Filimonova, N. I. & Ivkov, S. M. (1995). *Chem. Heterocycl. Compd (Engl. Transl.)*, **31**, 2, 167–175.